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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/506,309	YAMANO ET AL.	
Examiner	Art Unit	
Andrew B. Freistein	1626	

SEARCHED			
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Restriction	8/15/2005	ABF
STN (see attached)	11/4/2005	ABF
STN (see attached)	11/7/2005	ABF
STIC (see attached)	11/3/2005	ABF
STIC Inventor Name	11/3/2005	ABF
EDan Inventor Name	11/7/2005	ABF
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